


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517010	<b>Applicant(s)/Patent Under Reexamination</b>  COGHLAN ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
restriction requirement	8/2/2007	sl
stn structure	10-5-2007	sl
palm all inventors	10-5-2007	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner